



EB-6A mmW Probe Station

Optimized mmW Probe Station for
precise integration with
Anritsu Millimeter-Wave Modules

The EB-6A is a market proven solution developed closely together with Anritsu and provides the following features:

Features

- Customized Positioners Specifically For Anritsu Broadband Millimeter-Wave Modules
- Integrated Heat-Sink and Mount for Millimeter-Wave Modules
- Precise Integration Allowing Direct Link of Probes
- Double-Side mmW Probing Upgradeable
- Coaxial Style High Precision Stage
- Back-lash free movement
- 4.5" Probe Card Holder compatible
- Micropositioner Standby Dock

Applications

- High Performance RF
- Single Broadband Probing
- Differential mm-Wave
- Basic DC (IV/CV)

Accessories

- Hot Chuck with Auxiliary Chuck with Temperature Controller
- Vibration Free Table
- Shielding Box



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EB-6A PROBE STATION

Your Partner in Probing Solutions

Station Specifications

Station Footprint	760 mm W x 660mm D
Station Height	450 mm (to Platen)/700 mm (to Microscope)
Station Weight	80kg
Platen Material	Hard Chrome Plated Steel
Platen Dimension	250 mm Inner, 450mm Outer
Platen Capacity	12 DC or 4 RF and 4 DC
Positioner Mount	Magnetic ON/OFF Switch
No. of Vacuum Switches	4
Chuck Material	Stainless Steel
Chuck Stage Type	Coaxial
Chuck Travel Range	6" x 6"
Chuck Fine Resolution	1 μ m
Chuck Theta Coarse Travel	360°
Chuck Theta Fine Resolution	0.01°
Chuck Z-Motion Range	4 mm
Chuck Z-Fine Resolution	1 μ m
Coaxial Chuck Movement	Bevelled Gear and Rack 0.8 mm Pitch
Chuck Size	6" (150 mm)
Chuck Planarity	3 μ m
Chuck Rigidity	15 μ m / 10 N @ edge
Chuck Vacuum Grooves	Center, 0.5", 1.5", 2.5" (Individually Controlled)
Chuck Bias Capacity	Up to 2 kV
Chuck Isolation	5 G Ω
DUT Size Range	2 mm - 150 mm
Microscope Stage Type	High Precision Linear Stage
Microscope Stage Resolution	1 μ m
Microscope Stage Travel Range	2" x 2"
Microscope Tilting (Optional)	35°
Microscope Zoom Range	1x - 2x
Microscope Eye Piece	10x
Microscope Objectives	2x, 10x, 20x
Microscope Magnification Range	20x-400x



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mmW Micropositioner Features



EB-AN-125

Resolution: 0.8 μm

Travel Range: Linear 25 mm X-Y-Z

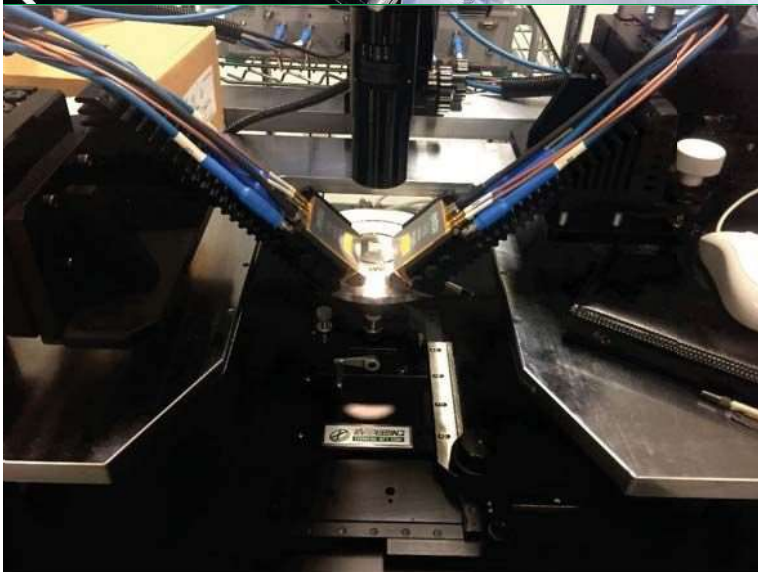
Dimensions: 150 mm W x 200 mm D x 86 mm H

Weight: 1200 g

Extender Compability: Anritsu 3743A/E, Anritsu MA25300A, Anritsu 3744A/E

Features:

- Integrated heat sink to cool mmW modules ensuring consistent performance when in use
- Angled arrangement allows direct connection to RF probes, removing the use of extra waveguides, reducing loss
- Backside probing option available for positioner



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Micropositioner Options

All micropositioners offer X-Y-Z linear-motion travel with no backlash with mounting options including magnet, vacuum or magnet switch



EB-050

Resolution: 0.8 μm

Screw Resolution: 212 μm

Travel Range: Linear 12 mm X-Y-Z

Dimensions: 52 mm W x 96 mm D x 76 mm H

Weight: 550 g

Use For: DC/RF Capable



EB-700

Resolution: 2 μm

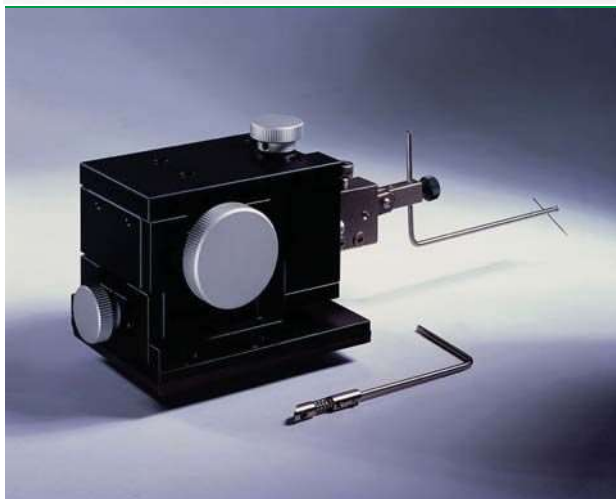
Screw Resolution: 630 μm

Travel Range: Linear 12 mm X-Y-Z

Dimensions: 38 mm W x 62 mm D x 45 mm H

Weight: 200 g

Used For: DC Only



EB-005

Resolution: 0.3 μm

Screw Resolution: 125 μm

Travel Range: Linear 12 mm X-Y-Z

Dimensions: 90 mm W x 130 mm D x 90 mm H

Weight: 1000 g

Used For: DC/RF Capable


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Vibration Free Table Option (Recommended)



VFT-4836

Dimension: 48" W x 36" D x 36" H
Vertical Natural Frequency: 1.5 Hz
Isolation Efficiency: @ 5 Hz 85%
Horizontal Natural Frequency: 1.2 Hz
Isolation Efficiency: @ 5 Hz 91%
Air Requirement: 80 psi
Net Load: 200 kg
Material: Stainless Steel TableTop

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